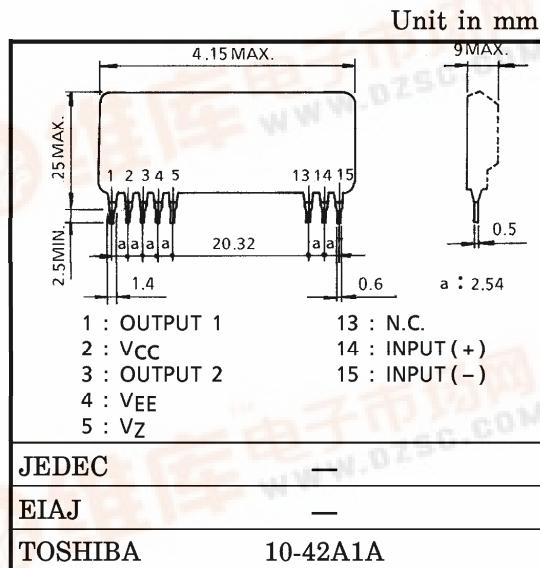


## TOSHIBA SOLID STATE IGBT GATE DRIVER MODULE

## TF1206

TOSHIBA TF1206 is the IGBT gate driver designed for use with TOSHIBA Insulated Gate Bipolar Transistor Module and it includes the optical isolator and IGBT gate driver circuit. Using this driver, you can design high reliability and compact system.

- Recommended Conditions :
  - Input Current :  $I_F = 7.5\text{mA}$
  - Output Supply Voltage :  $V_{CC} = 15\text{V}$ ,  $V_{EE} = -15\text{V}$
- High Speed Switching Response :
  - $t_{PLH} = 0.5\mu\text{s}$  (Typ.)
  - $t_{PHL} = 0.4\mu\text{s}$  (Typ.)
- Small Size and Light Weight
- 2500 VAC Optical Isolation

MAXIMUM RATINGS ( $T_a = 25^\circ\text{C}$ )

| CHARACTERISTIC                          | SYMBOL      | RATING                | UNIT |
|---|-------------|-----------------------|------|
| Input Current                           | $I_F$       | 20                    | mA   |
| Reverse Input Voltage                   | $V_R$       | 5                     | V    |
| Output Supply Voltage                   | $V_{CC}$    | 18                    | V    |
|   | $V_{EE}$    | -18                   |      |
| Output Voltage                          | $V_{OUT}$   | $V_{CC} \sim V_{EE}$  | V    |
| High Level Peak Output Current (Note 1) | $I_{OHP}$   | 2 ( $10\mu\text{s}$ ) | A    |
| Low Level Peak Output Current (Note 1)  | $I_{OLP}$   | -3 ( $5\mu\text{s}$ ) | A    |
| Operating Frequency (Note 2)            | f           | 30                    | kHz  |
| Isolation (Input-Output)                | $BV_S / AC$ | 2500 (1min)           | V    |
| Operating Temperature                   | $T_{opr}$   | -20 ~ 70              | °C   |
| Storage Temperature                     | $T_{stg}$   | -20 ~ 85              | °C   |
| Lead Soldering Temperature              | $T_{sol}$   | 260°C (10s)           | °C   |

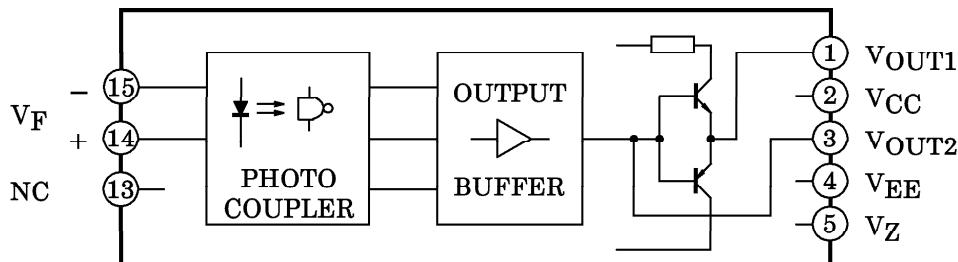
Note 1 : Exponential Waveform ( $f=15\text{kHz}$ , Fig.1)

Note 2 :  $I_{OHP}=2\text{A}$  ( $5\mu\text{s}$ ),  $I_{OLP}=-3\text{A}$  ( $5\mu\text{s}$ ), Exponential Waveform (Fig.1)

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## BLOCK DIAGRAM

ELECTRICAL CHARACTERISTICS ( $T_a = 25^\circ\text{C}$ ,  $V_C = 5\text{V}$ ,  $V_{CC} = 5\text{V}$ ,  $V_{EE} = -15\text{V}$ ,  $R_Z = 500\Omega$ ,  $f = 10\text{kHz}$ )

| CHARACTERISTIC                                      | SYMBOL    | TEST CONDITION   | MIN. | TYP.      | MAX. | UNIT                    |
|---|-----------|--|------|-----------|------|-------------------------|
| High Level Input Voltage                            | $V_{FT}$  | $V_{OUT1} > 0\text{V}$ (Fig.2, 3)                                  | —    | 1.5       | 1.6  | $\text{V}$              |
| High Level Input Current                            | $I_{FT}$  | $V_{OUT1} > 0\text{V}$ (Fig.2, 3)                                  | —    | 1.5       | 7.5  | $\text{mA}$             |
| Reverse Current                                     | $I_R$     | $V_R = 5\text{V}$  | —    | —         | 10   | $\mu\text{A}$           |
| High Level Output Voltage                           | $V_{OH}$  | $I_F = 7.5\text{mA}$ , $R_L = 200\Omega$ (Fig.2, 3)                | 13   | 13.5      | —    | $\text{V}$              |
| Low Level Output Voltage                            | $V_{OL}$  | $I_F = 0\text{mA}$ , $R_L = 200\Omega$ (Fig.2, 3)                  | —    | -13.5     | -13  |                         |
| High Level Supply Current                           | $I_{CCH}$ | $I_F = 7.5\text{mA}$ , $V_{OUT1} > 0\text{V}$ (Fig.2, 3)           | —    | 25        | —    | $\text{mA}$             |
| Low Level Supply Current                            | $I_{CCL}$ | $I_F = 0\text{mA}$ , $V_{OUT1} < 0\text{V}$ (Fig.2, 3)             | —    | 20        | —    |                         |
| Zener Voltage (Coupler Supply)                      | $V_Z$     | $I_Z = 20\text{mA}$ , 4pin to 5pin                                 | —    | 5.1       | —    | $\text{V}$              |
| Propagation Delay Time to High Output Level         | $t_{pLH}$ | $I_F = 7.5\text{mA}$ , $V_{OUT1} > 0\text{V}$<br>$R_L = 200\Omega$ | —    | 0.5       | 1.0  | $\mu\text{s}$           |
| Output Rise Time                                    | $t_r$     | (Fig.2, 3)   | —    | 0.25      | —    |                         |
| Propagation Delay Time to Low Output Level          | $t_{pHL}$ | $I_F = 0\text{mA}$ , $V_{OUT1} < 0\text{V}$<br>$R_L = 200\Omega$   | —    | 0.4       | 0.8  | $\mu\text{s}$           |
| Output Fall Time                                    | $t_f$     | (Fig.2, 3)   | —    | 0.10      | —    |                         |
| Common Mode Transient Immunity at Logic High Output | $CM_H$    | $V_{CM} = 400\text{V}$   | 1    | 10        | —    | $\text{kV}/\mu\text{s}$ |
| Isolation Resistance (Input-Output)                 | $R_S$     | $V = 1\text{kV}$ , $RH = 40\sim60\%$                               | —    | $10^{10}$ | —    | $\Omega$                |

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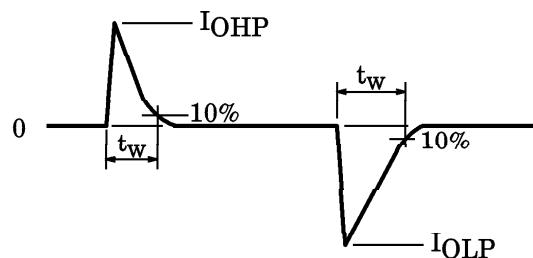


Fig.1 EXPONENTIAL WAVEFORM

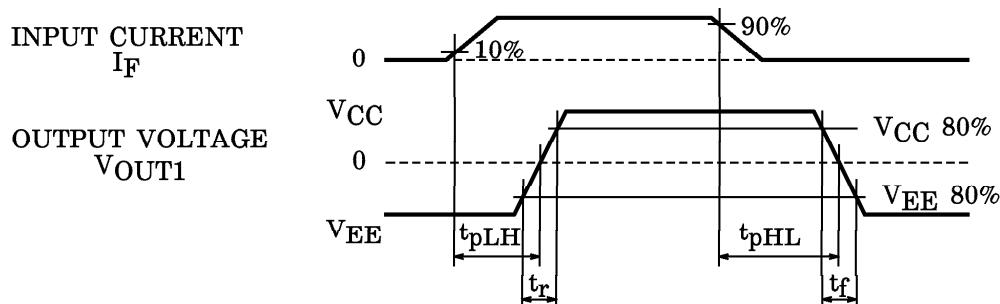


Fig.2 SWITCHING TIME TEST CONDITION

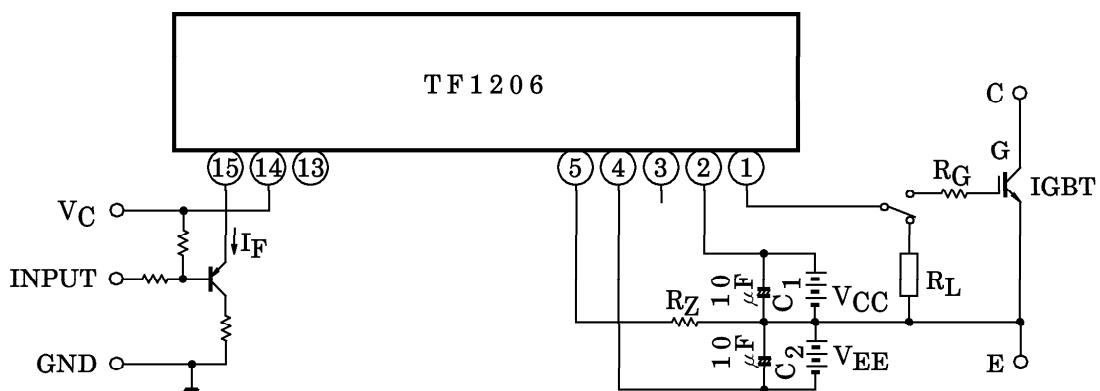


Fig.3 SWITCHING TIME TEST CIRCUIT

